United States Patent [19]

Yamamoto et al.

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[45] **Date of Patent: ** Jul. 31, 1984**

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[54] **MICROMETER**

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[73] Assignee: **Mitutoyo Mfg. Co., Ltd.,** Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **349,195**

[22] Filed: **Feb. 17, 1982**

[30] **Foreign Application Priority Data**

Sep. 4, 1981 [JP] Japan 56-39105

[52] **U.S. Cl.** **D10/73**

[58] **Field of Search** .... D10/73; 33/143 F, 147 F, 33/147 G, 147 J, 147 T, 147 R, 166 R, 172 R

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Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—Flynn, Thiel, Boutell & Tanis

[57] **CLAIM**

The ornamental design for the micrometer, as shown and described.

DESCRIPTION

FIG. **1** is a front and top-right perspective view of a micrometer showing our new design;

FIG. **2** is a top plan view thereof;

FIG. **3** is a bottom plan view thereof;

FIG. **4** is a front elevational view thereof;

FIG. **5** is a rear elevational view thereof;

FIG. **6** is a left side elevational view thereof;

FIG. **7** is a right side elevational view thereof;

FIG. **8** is a cross-sectional view as taken from line A—A of FIG. **4**; and

FIG. **9** is a cross-sectional view as taken from line B—B of FIG. 4.

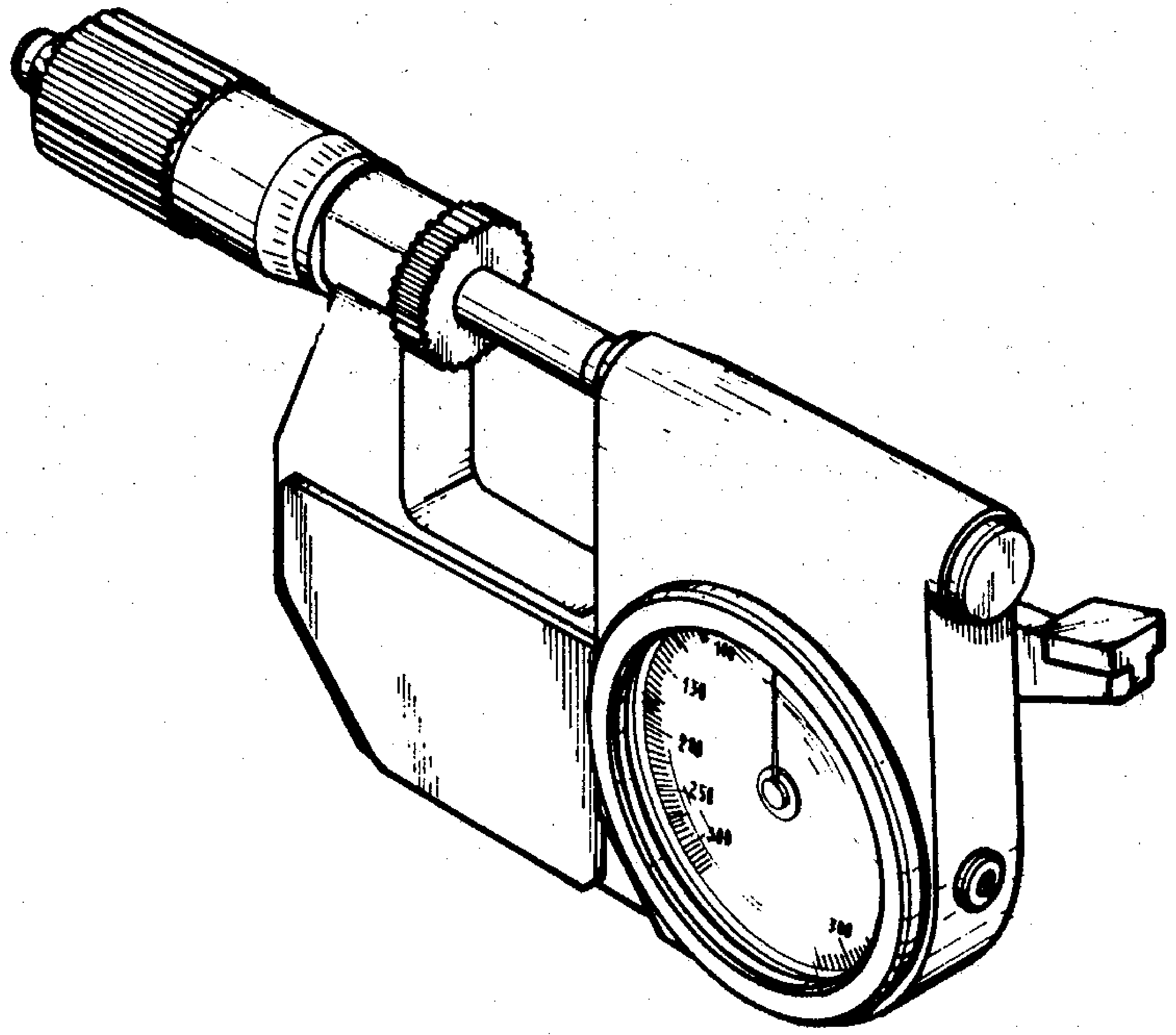

FIG. 1

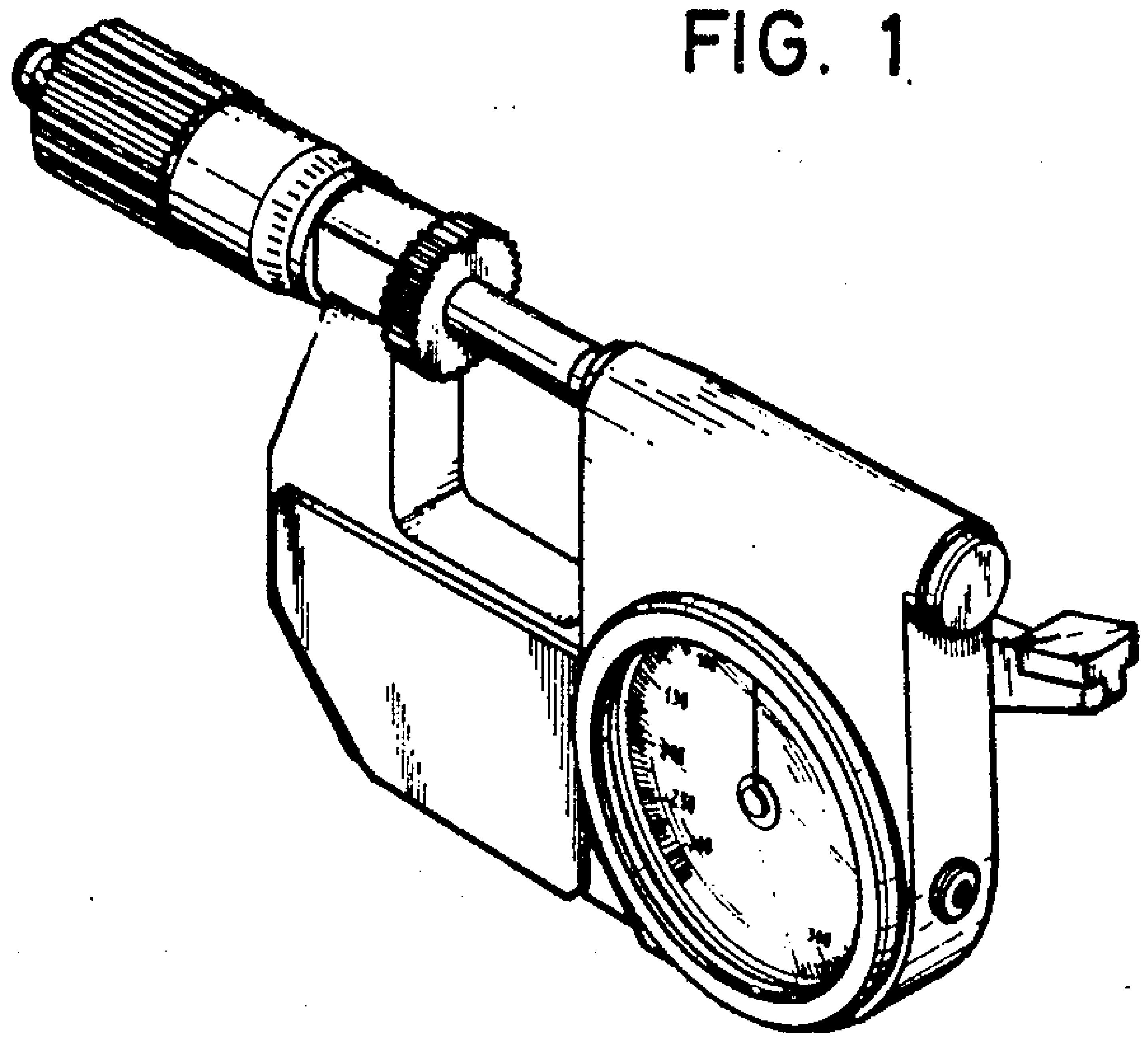

FIG. 2

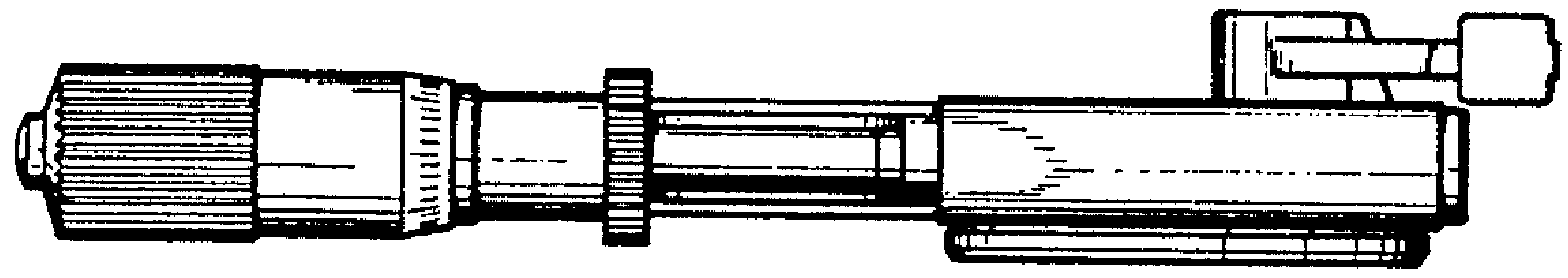

FIG. 3

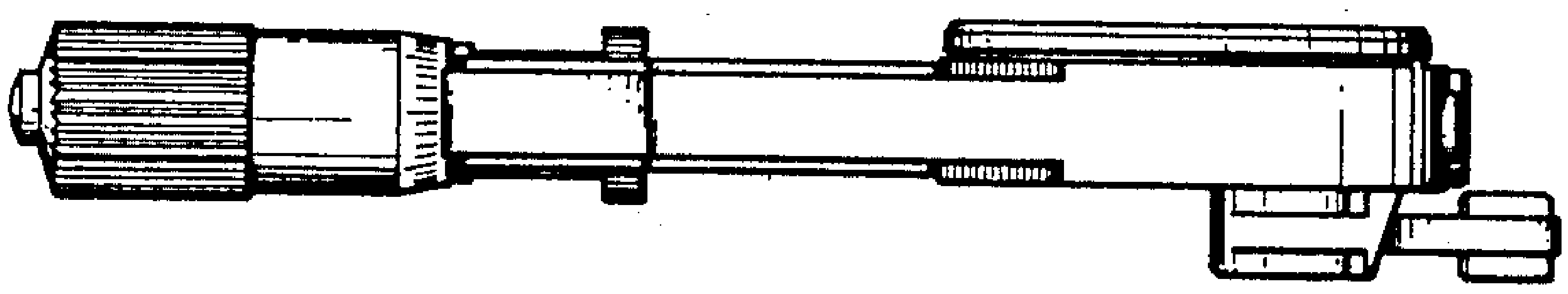

FIG. 4

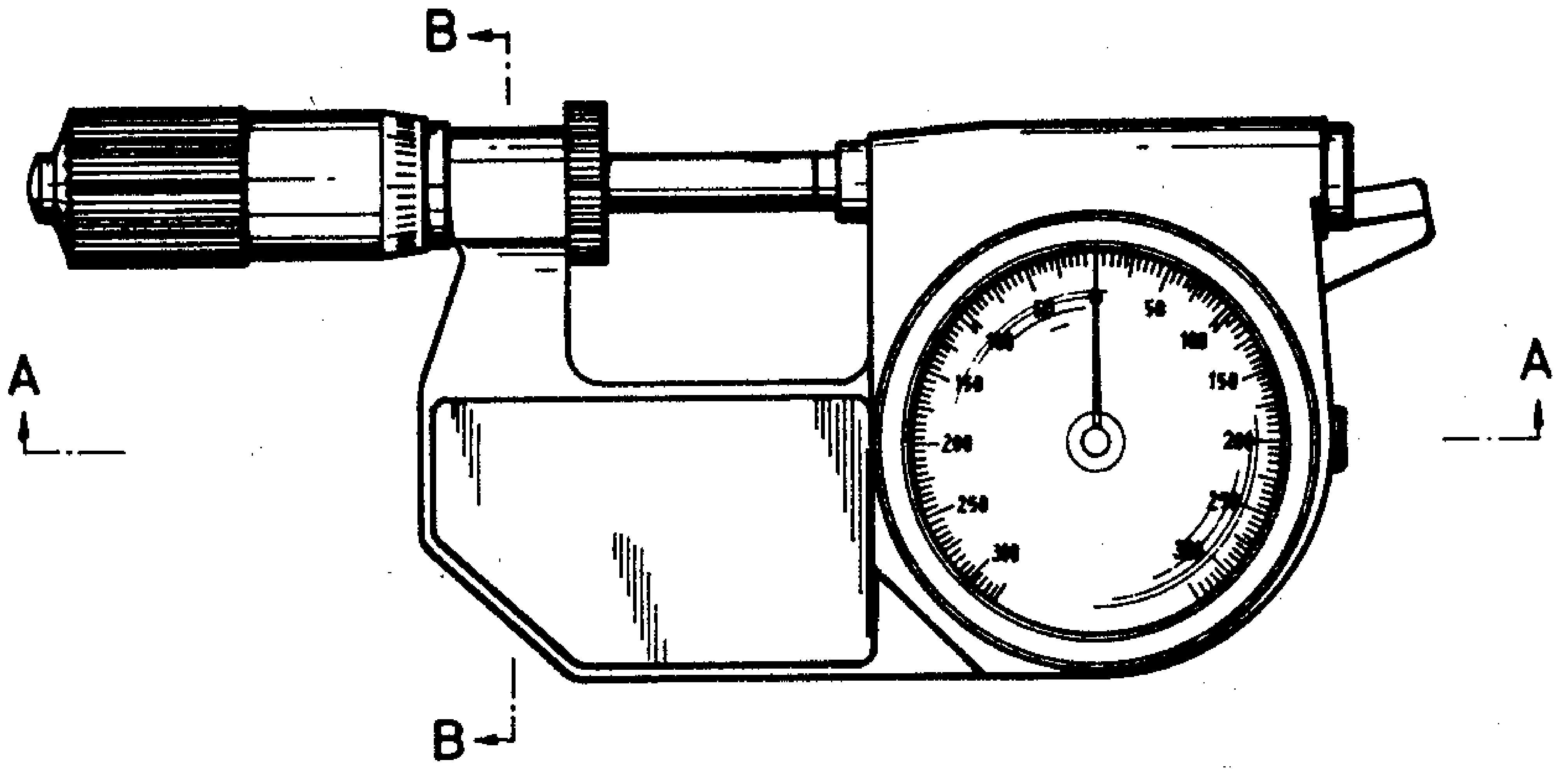

FIG. 5

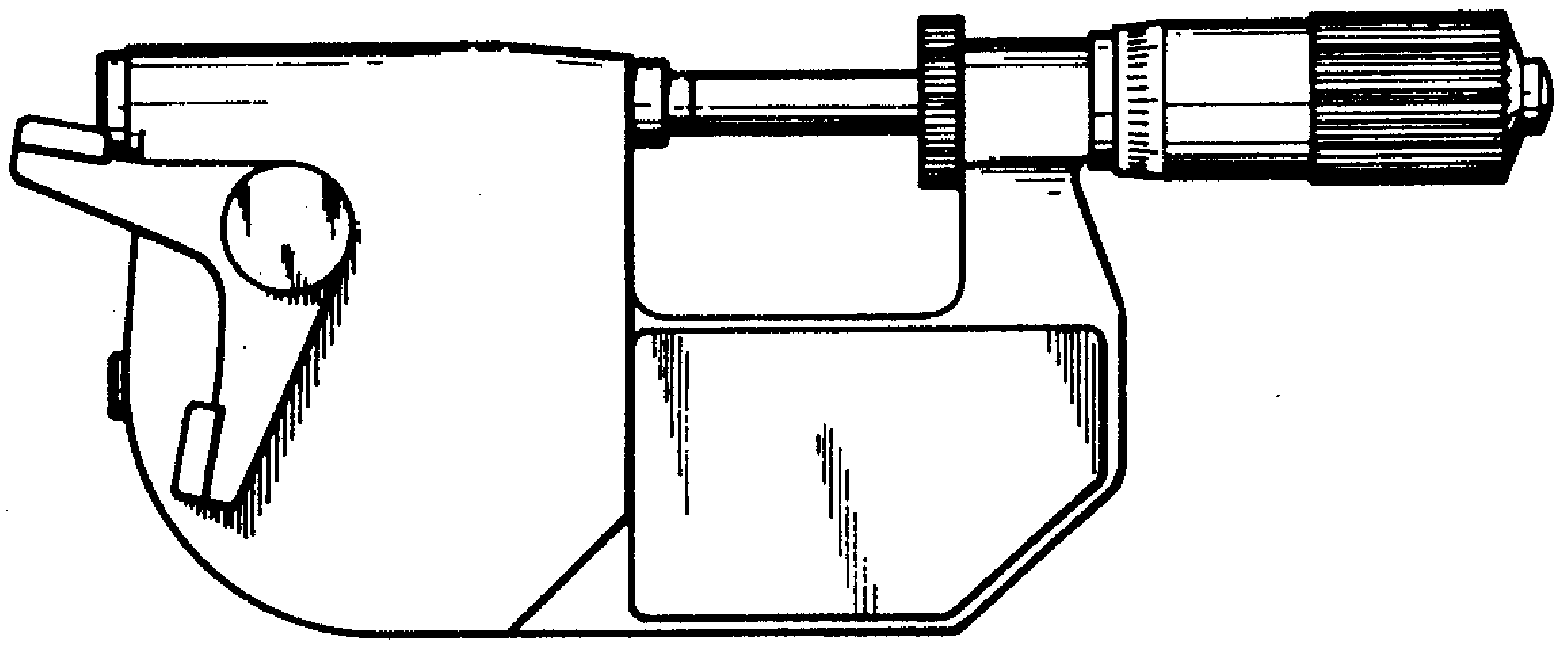

FIG. 6

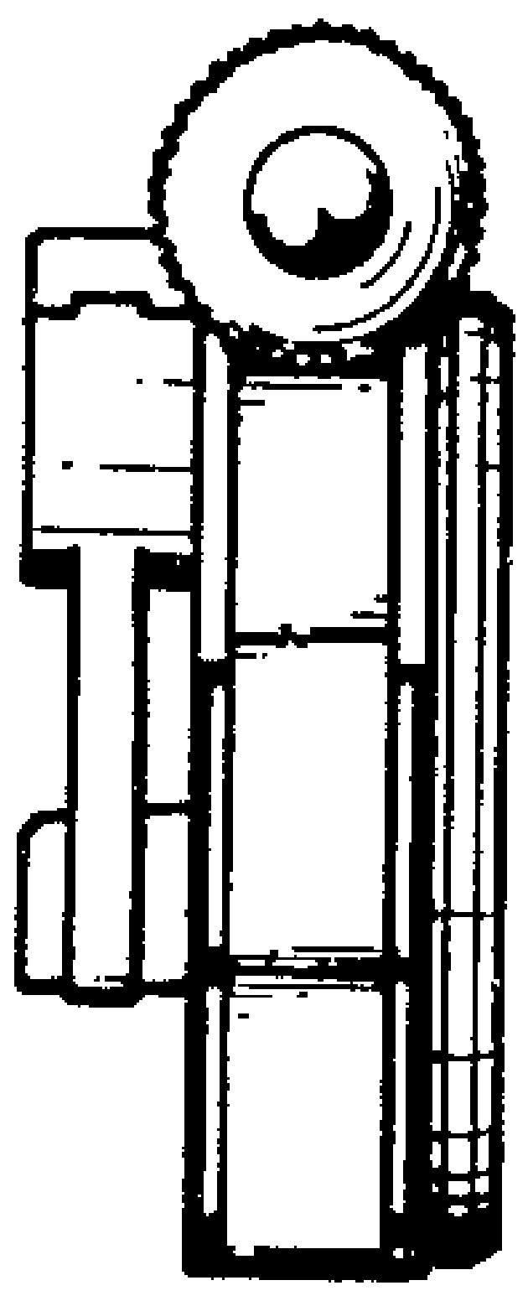

FIG. 7

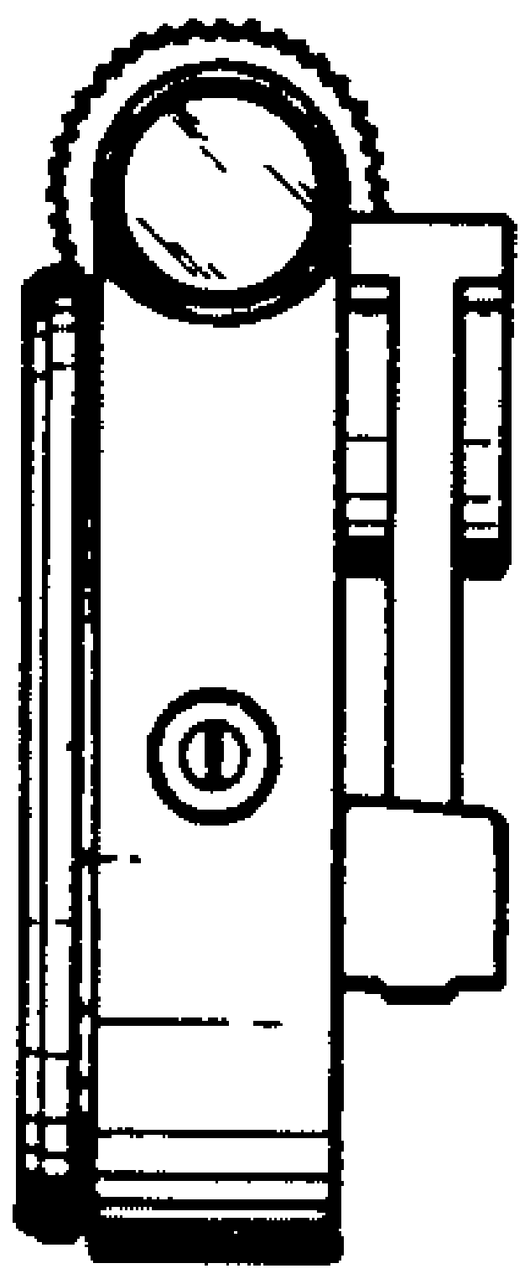

FIG. 8

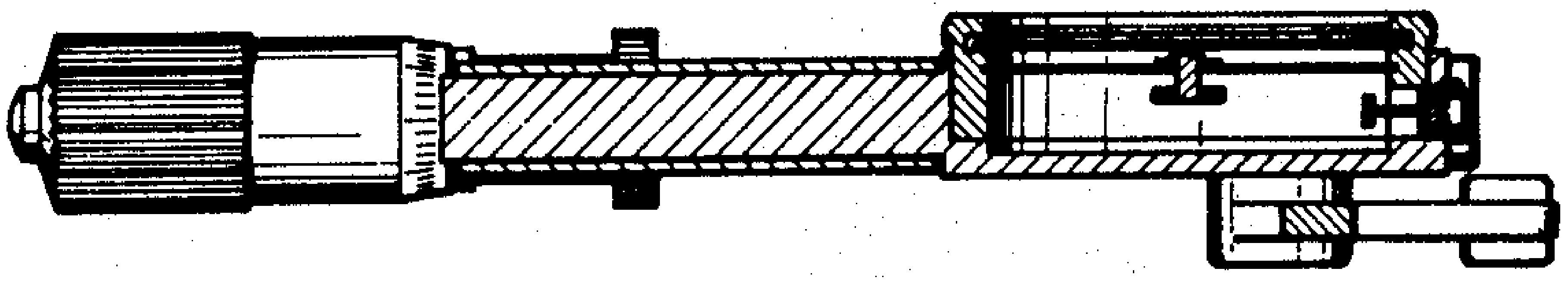

FIG. 9